Special Issue

Methods and Architectures for Dependability of Embedded or Integrated Systems

Message from the Guest Editor

This Special Issue looks for original papers presenting ways to improve and/or validate any dependability attribute of embedded or integrated systems (in particular safety, availability, and/or security), either at block level, circuit level or in electronic control units, used in many industrial contexts. Contributions are being sought on methods (methodology, algorithms, tools, etc.), descriptions of new or optimized hardware/software functions or building blocks (IPs), or real-life application demonstrations with optimized system-level assembling of existing blocks. Taking advantage of emerging technologies to improve dependability attributes is another possibility, as any new proposed direction in the global scope.

Guest Editor

Prof. Régis Leveugle
Grenoble Alpes University, CNRS, Grenoble INP, TIMA, 38000 Grenoble, France

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Deadline for manuscript submissions

closed (31 December 2021)

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Applied Sciences
Editorial Office
MDPI, Grosspeteranlage 5
4052 Basel, Switzerland
Tel: +41 61 683 77 34
applsci@mdpi.com

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

Prof. Dr. Giulio Nicola Cerullo
Dipartimento di Fisica, Politecnico di Milano, Piazza L. da Vinci 32,
20133 Milano, Italy

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